5 TEST RESULTS

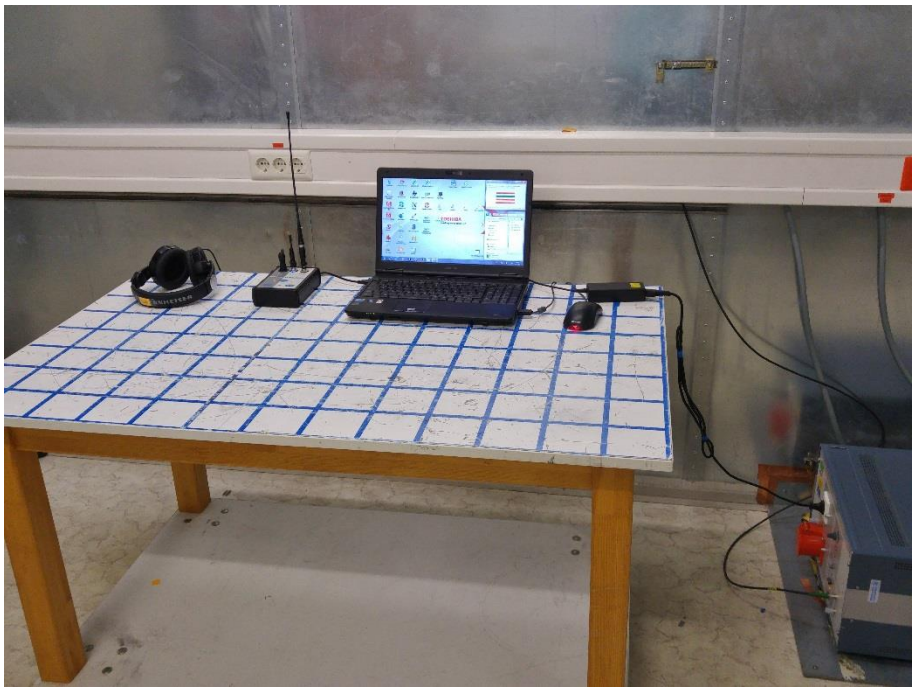
5.1 Conducted emissions

For test instruments and accessories used, see section 6 Part **A 4**.

5.1.1 Description of the test location

Test location: Shielded Room S2

5.1.2 Photo documentation of the test set-up



5.2 Maximum output power radiated

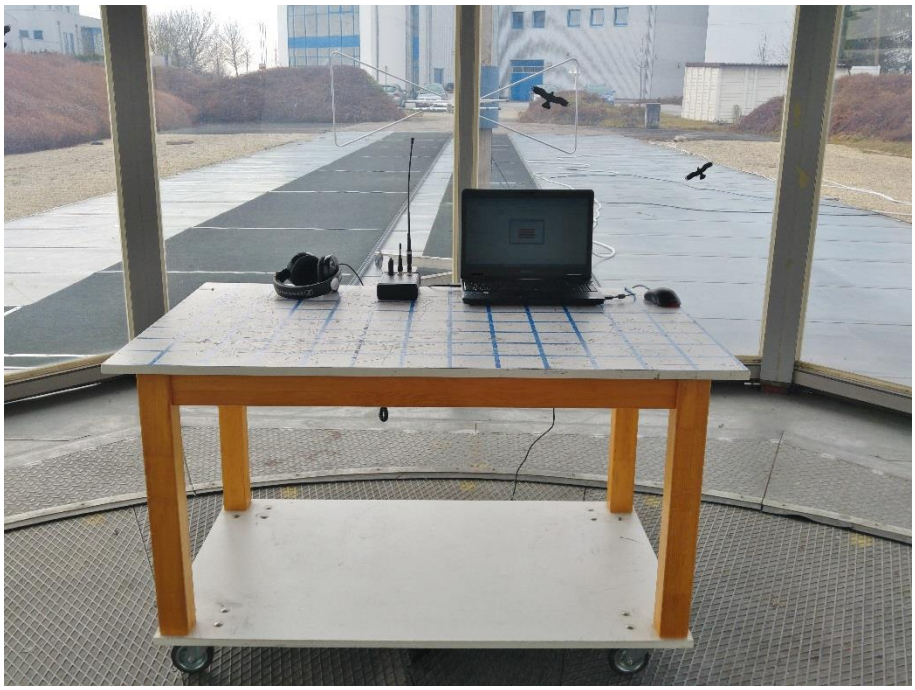
For test instruments and accessories used see section 6 Part **CPR 2**.

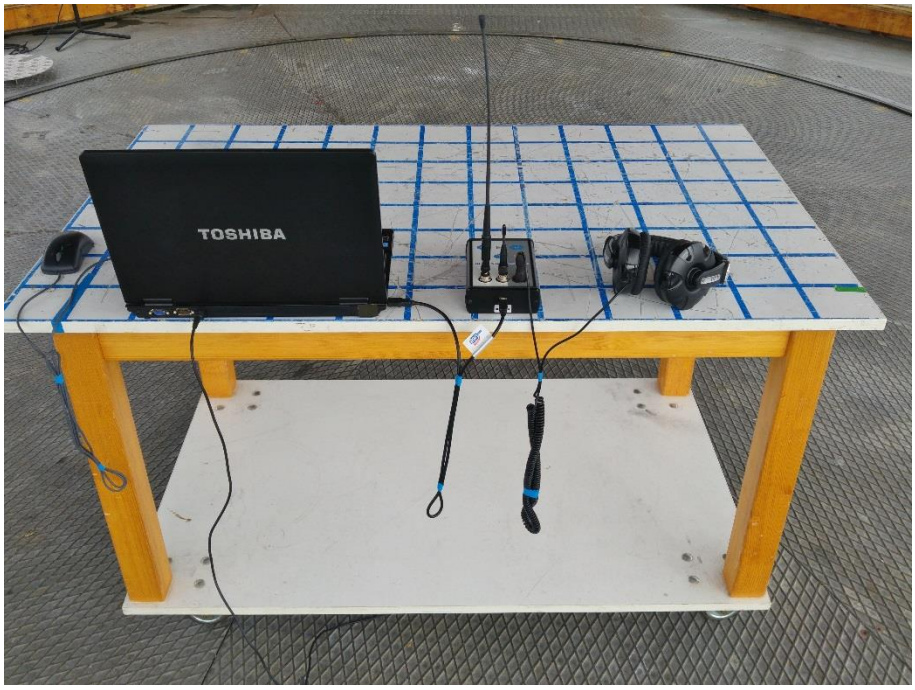
5.2.1 Description of the test location

Test location: OATS 1

Test distance: 10 m

5.2.2 Photo documentation of the test set-up





5.3 Spurious emissions radiated (electric field)

For test instruments and accessories used see section 6 Part **SER 2, SER 3**.

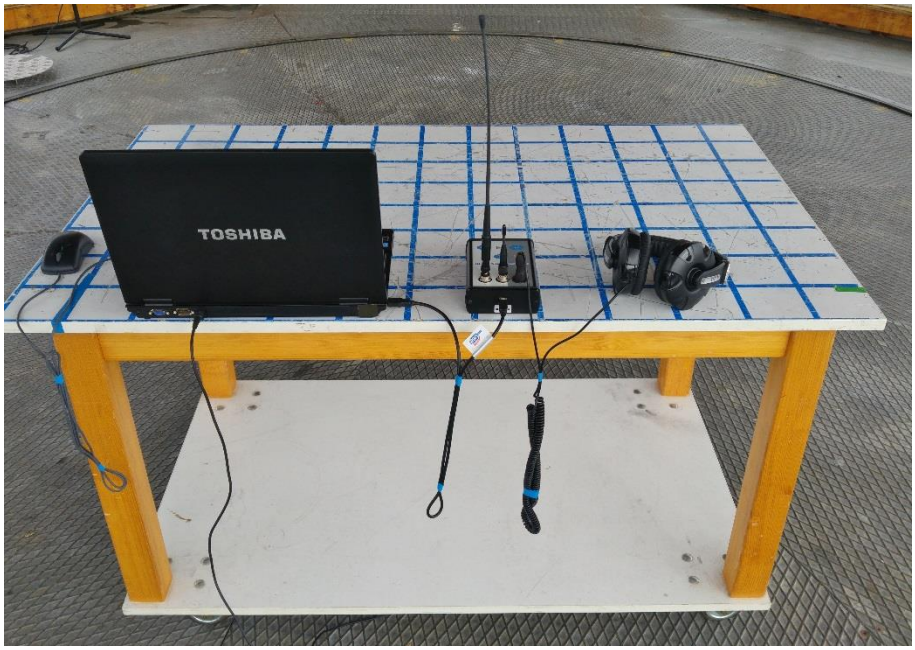
5.3.1 Description of the test location

Test location: OATS 1
Test distance: 10 m

Test location: Anechoic chamber 1
Test distance: 3 m

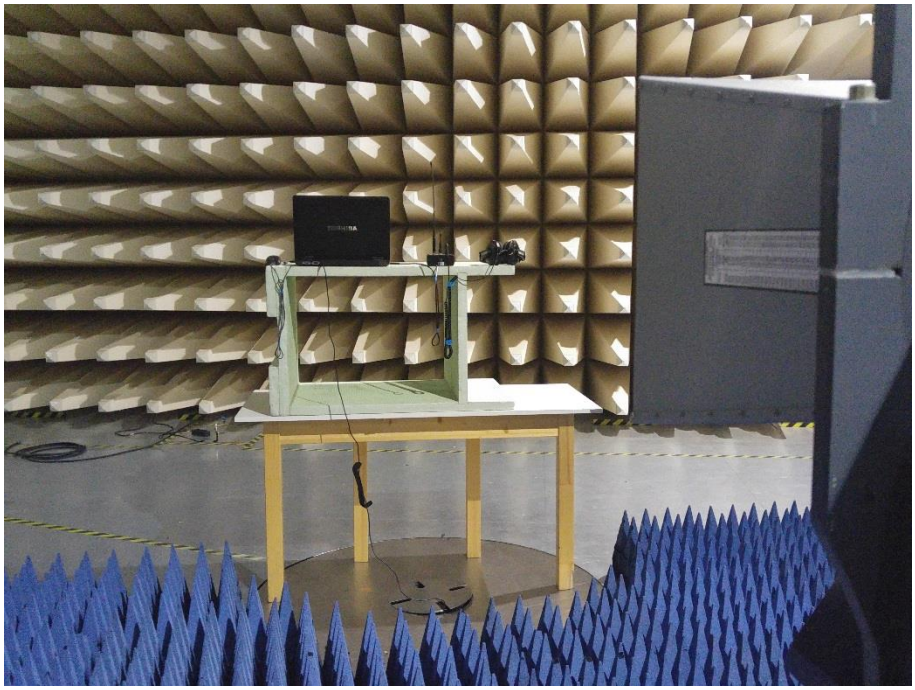
5.3.2 Photo documentation of the test set-up

OATS1 – 10 m – 30 MHz to 1000 MHz

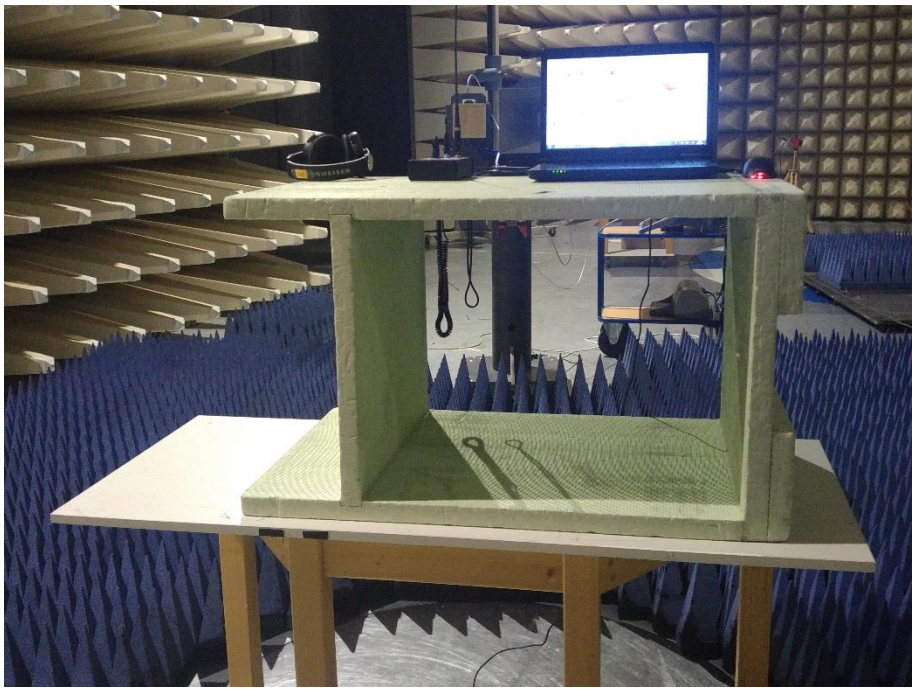


OATS1 – 10 m – 30 MHz to 1000 MHz

FCC ID: OV8-CORC300RI



A1 – 3 m – 1 GHz to 12.75 GHz



A1 – 3 m – 1 GHz to 12.75 GHz

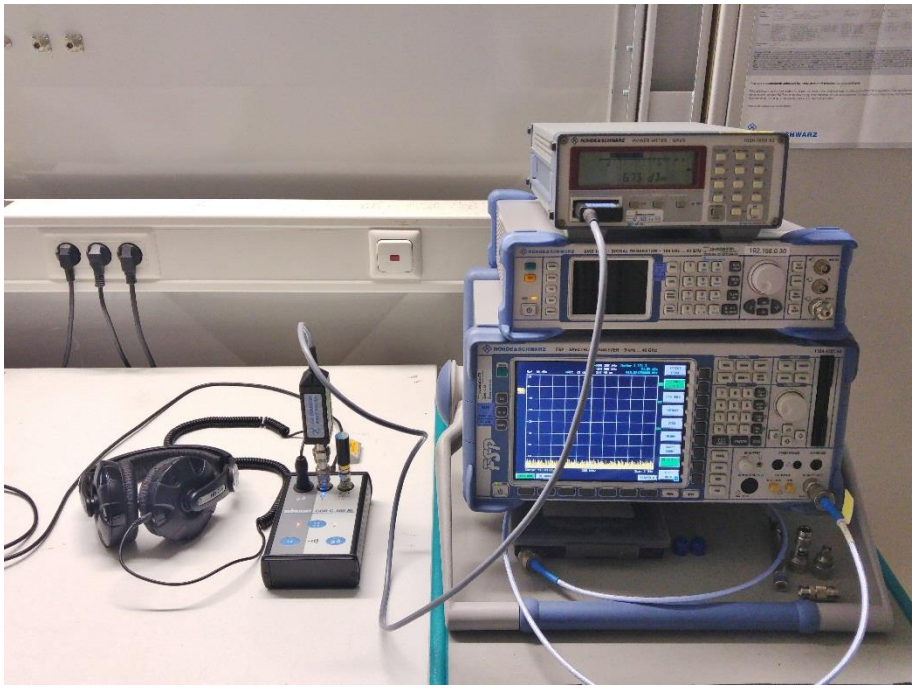
5.4 Conducted carrier output power

For test instruments and accessories used see section 6 Part **CPC 2**.

5.4.1 Description of the test location

Test location: Shielded Room S4

5.4.2 Photo documentation of the test set-up



5.4.3 Applicable standard

According to FCC Part 90.217:
Except as noted herein, transmitters used at stations licensed below 800 MHz on any frequency listed in subparts B and C of this part or licensed on a business category channel above 800 MHz which have an output power not exceeding 120 mW are exempt from the technical requirements set out in this subpart, but must instead comply with the following:
(a) For equipment designed to operate with a 25 kHz channel bandwidth, the sum of the bandwidth occupied by the emitted signal plus the bandwidth required for frequency stability shall be adjusted so that any emission appearing on a frequency 40 kHz or more removed from the assigned frequency is attenuated at least 30 dB below the unmodulated carrier.

5.4.4 Description of Measurement

The maximum conducted carrier output power is measured using a power meter in a test setup following the procedures set out in ANSI/TIA-603-D Section 2.2.1. The EUT is set in TX continuous mode while measuring.

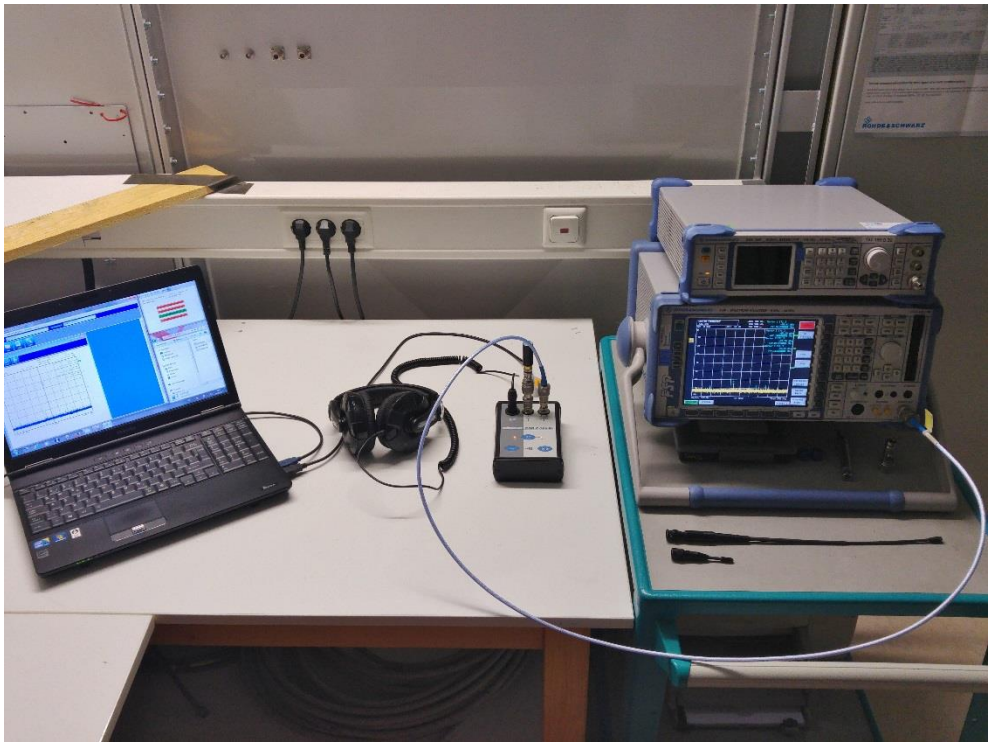
5.5 Conducted spurious emissions

For test instruments and accessories used see section 6 Part **SEC 1-3**.

5.5.1 Description of the test location

Test location: Shielded Room S4

5.5.2 Photo documentation of the test set-up



5.5.3 Applicable standard

According to FCC Part 90.217(a):
(a) For equipment designed to operate with a 25 kHz channel bandwidth, the sum of the bandwidth occupied by the emitted signal plus the bandwidth required for frequency stability shall be adjusted so that any emission appearing on a frequency 40 kHz or more removed from the assigned frequency is attenuated at least 30 dB below the unmodulated carrier.

5.5.4 Description of Measurement

The spurious emissions are measured conducted using a spectrum analyser in a test setup following the procedures set out in ANSI/TIA-603-D Section 2.2.13. The measurement is performed at normal test conditions in modulated TX continuous mode.

Instrument settings:

9 kHz – 1000 MHz:	RBW: 100 kHz
1000 MHz – 12750 MHz	RBW: 1 MHz

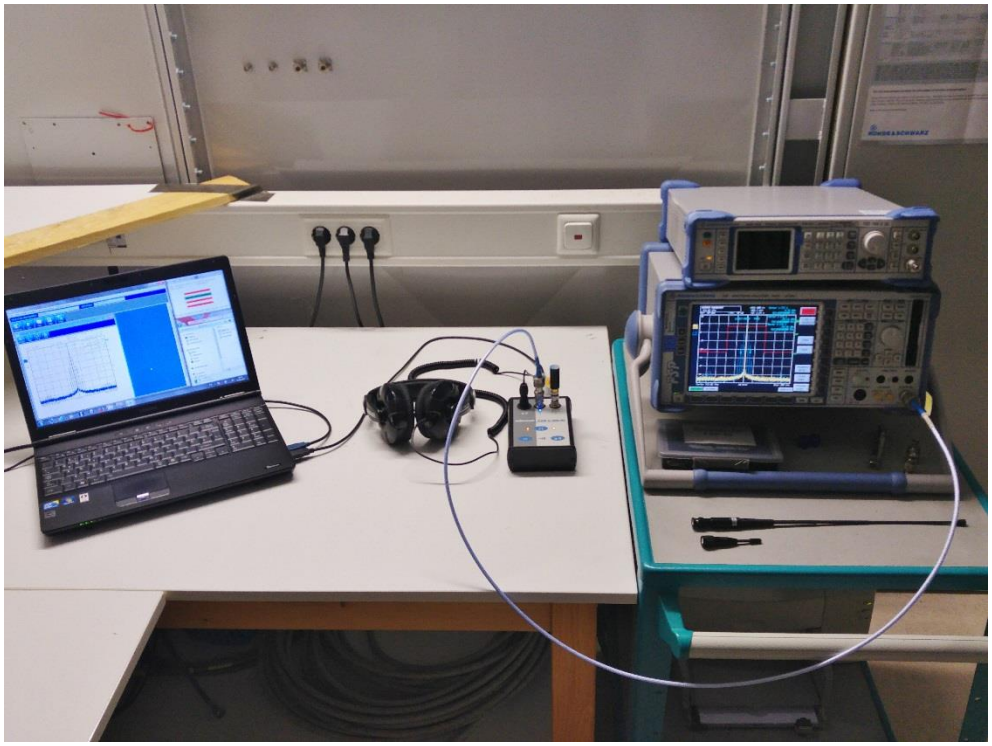
5.6 Modulation characteristics

For test instruments and accessories used see section 6 Part **MB**.

5.6.1 Description of the test location

Test location: Shielded Room S4

5.6.2 Photo documentation of the test set-up



5.6.3 Applicable standard

According to FCC Part 90.217(a):
(a) For equipment designed to operate with a 25 kHz channel bandwidth, the sum of the bandwidth occupied by the emitted signal plus the bandwidth required for frequency stability shall be adjusted so that any emission appearing on a frequency 40 kHz or more removed from the assigned frequency is attenuated at least 30 dB below the unmodulated carrier.

5.6.4 Description of Measurement

The measurement was performed conducted with intentional modulation on and off. The emission mask defined for 25 kHz channel bandwidth devices is shown on each plot. The 0 dB reference for the mask is the measured output power of the unmodulated carrier at that frequency.

Spectrum analyser settings:
RBW: 300 Hz, VBW: 1 kHz, Detector: PK sampling detector, Sweep time: auto

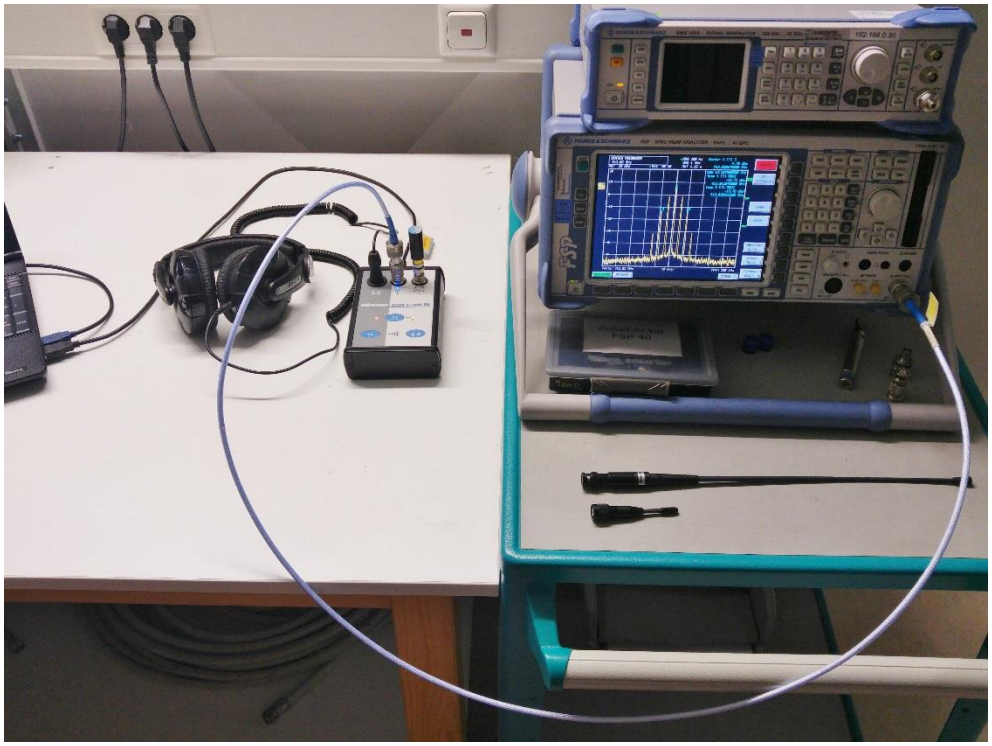
5.7 Occupied bandwidth

For test instruments and accessories used see section 6 Part **MB**.

5.7.1 Description of the test location

Test location: Shielded Room S4

5.7.2 Photo documentation of the test set-up



5.7.3 Applicable standard

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 per cent of the total mean power radiated by a given emission shall be measured under the following conditions as applicable:
Transmitters in which the modulating baseband comprises not more than three independent channels—when modulated by the full complement of signals for which the transmitter is rated. The level of modulation for each channel should be set to that prescribed in rule parts applicable to the services for which the transmitter is intended. If specific modulation levels are not set forth in the rules, the tests should provide the manufacturer's maximum rated condition.

5.7.4 Description of Measurement

The bandwidth was measured conducted with the function “bandwidth measurement” of the spectrum analyser.

Spectrum analyser settings:
RBW: 300 Hz, VBW: 1 kHz, Detector: PK sampling detector, Sweep time: auto

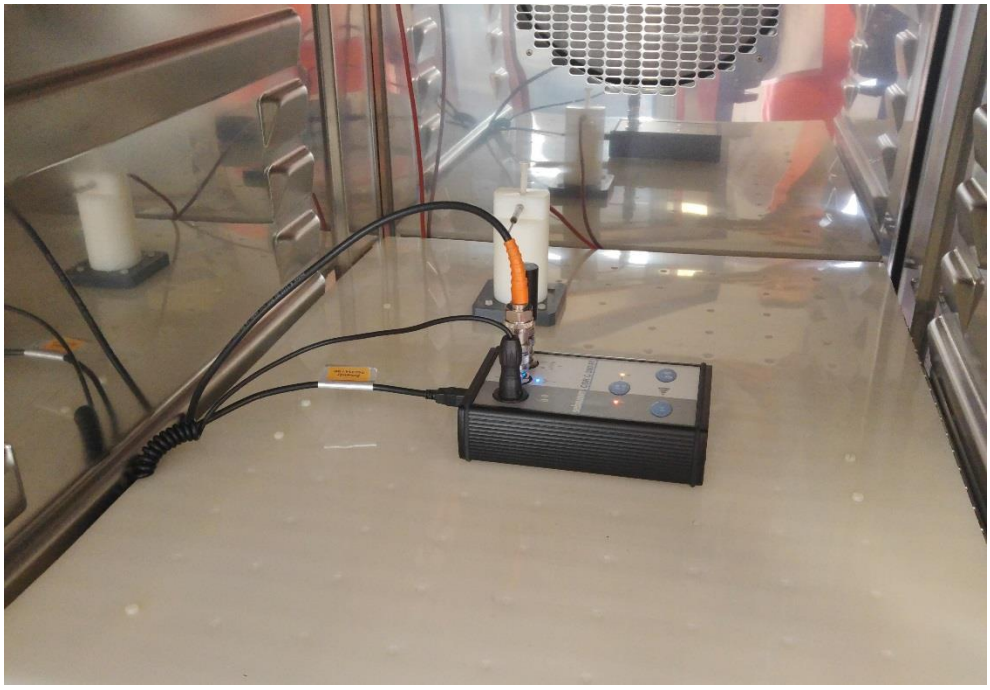
5.8 Frequency stability

For test instruments and accessories used see section 6 Part **MB**.

5.8.1 Description of the test location

Test location: AREA4

5.8.2 Photo documentation of the test set-up



5.9 Receiver spurious emissions, radiated

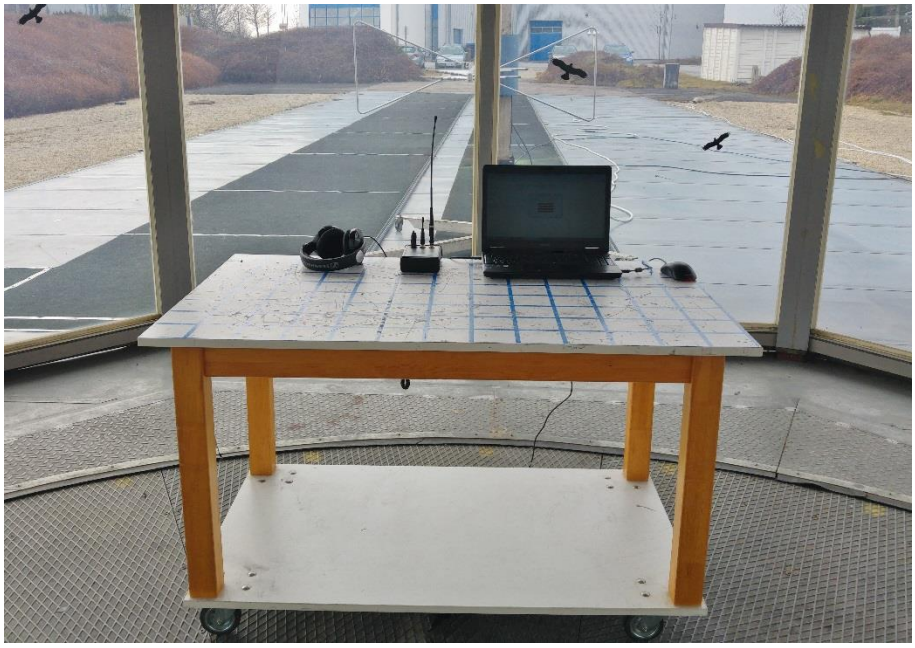
For test instruments and accessories used see section 6 Part **SER 2, SER 3**.

5.9.1 Description of the test location

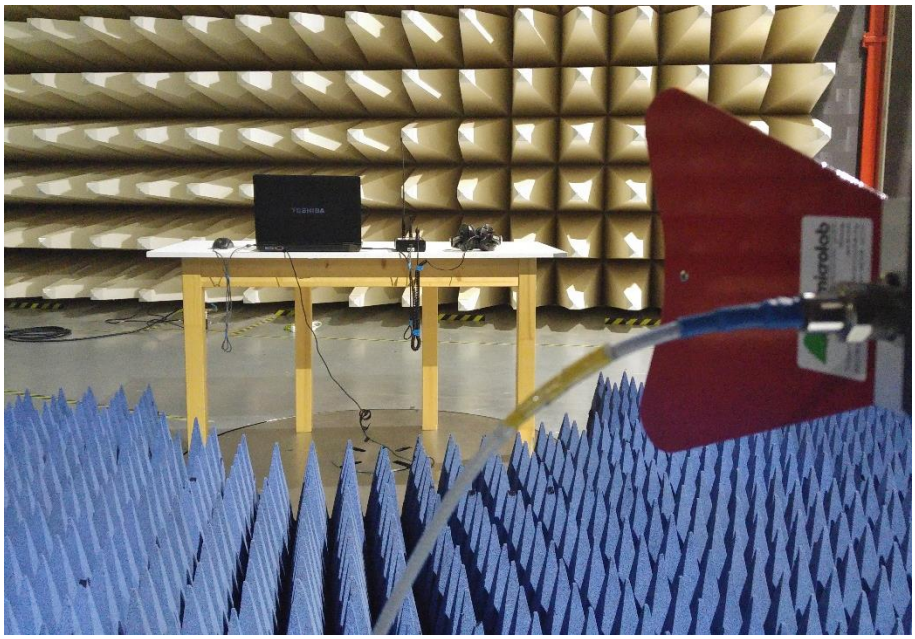
Test location: OATS 1
Test distance: 3 m

Test location: Anechoic chamber 1
Test distance: 3 m

5.9.2 Photo documentation of the test set-up



OATS1 – 10 m – 30 MHz to 1000 MHz



A1 – 3 m – 1 GHz to 12.75 GHz